

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	3073	356/237	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/11/29 13:24
S2	1829	asml.as.	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/11/29 13:25
S3	1583	lithograph\$4 and S2	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/11/29 13:38
S4	53	"5812563" "6252412" "6426168" 2002/121915	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/11/29 13:34
S5	54	"5812563" "6252412" "6426168" "2002121915"	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/11/29 13:34
S6	4	((("5812563") or ("6252412") or ("6426168") or ("2002121915"))).PN.	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2005/11/29 13:34
S7	4	((("5812563") or ("6252412") or ("6426168") or ("2002121915"))).PN.	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2005/11/29 13:35
S8	152	allawi	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/11/29 13:41
S9	0	allawi.xa.	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/11/29 13:41
S10	493	toatley.xa.	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/11/29 13:42
S11	815	toatley.xp.	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/11/29 15:09
S12	2	S3 and S1	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/11/30 11:21

S13	3073	356/237	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/11/30 11:21
S14	1829	asml.as.	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/11/30 11:21
S15	1583	lithograph\$4 and S14	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/11/30 11:21
S16	2	S15 and S13	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/11/30 11:21
S17	0	S16 and defect and pattern	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/11/30 11:21
S18	0	S16 and defect	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/11/30 11:22
S19	2	S16	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/11/30 11:23
S20	194	S13 and lithograph\$4	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/11/30 11:23
S21	101	S20 and defect	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/11/30 11:23
S22	93	S21 and pattern\$3	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/11/30 11:57
S23	89	S22 and wafer	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/11/30 11:59
S24	73	S20 and (defect near2 detect\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/11/30 12:05

S25	68	S24 and pattern\$3	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/11/30 12:05
S26	65	S25 and wafer	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/11/30 12:05
S27	1	"20040130711"	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2005/12/01 15:10
S28	3073	356/237	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/12/06 16:29
S29	194	S28 and lithograph\$4	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/12/06 16:29
S30	73	S29 and (defect near2 detect\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/12/06 16:29
S31	68	S30 and pattern\$3	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/12/06 16:29
S32	65	S31 and wafer	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2005/12/06 16:29
S33	0	S32 and (majority adj vote)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2005/12/06 16:37
S34	207	defect same vot\$3	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2005/12/06 16:38
S35	2	S28 and S34	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2005/12/06 16:38
S36	1	"6252142"	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2005/12/07 10:23

S37	47	"6252412"	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2005/12/07 10:23
S38	1	"6252412".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	OFF	2005/12/07 10:23